Search Notes (continued)

Application/Control No	. Applicant(s)/Patent under Reexamination
10/722,838	BOON, SUAN JEUNG
Examiner	Art Unit
James M. Mitchell	2813

SEARCHED				
Class	Subclass	Date	Examiner	
		1		
	<del></del>			

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u> </u>				
			ł		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Eas f (See printent)	2/17/04	Mir		
257/777, [21.526 [23.085] (Sec printout)				
438/598 67,107 110,406,455 (see pantout)				